

The present invention relates to inorganic particles comprising at least two chemical elements in a predefined and analytically identifiable ratio. These particles are used as a marking means incorporated into or applied onto any desired article. They provide a high security potential against counterfeiting since the analysis depends on a combination of spatial as well as of chemical information. In a first step the information containing particle has to be localized by scanning electron microscopy and in a second step the ratio of elements is analysed using energy- or wavelength-dispersive X-ray analysis (SEM/EDX).